

Search Notes

Application/Control No.

10/635,665

Examiner

Jeffrey G. Hoekstra

Applicant(s)/Patent under
Reexamination

MURAYAMA ET AL.

Art Unit

3736

SEARCHED

Class	Subclass	Date	Examiner
600	585	12/13/2005	JGH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR